

CTS-THERMAL-SHOCK-TEST-CHAMBERS

the latest generation with innovative technique future-oriented design. Extreme temperature changes up to 100 K/min. CTS-Thermal-Shock-Test-Chambers comply with current national and international standards (DIN, BS, Mil). Long term testing up to 3000 cycles.



Standard-Version of the product line „TSS“:

- ▶ multicolour touchpanel / 32 Bit Controller
- ▶ RS 232 interface
- ▶ potential free contact for malfunction signal
- ▶ Error display in plain text
- ▶ single-hand operated door handle; lockable
- ▶ entry port, depending on size of cabinet
- ▶ Observation window
- ▶ air dryer system to avoid freezing in long-time testing

Your benefits:

- ▶ Complies with current CE and EMC regulation
- ▶ use of environmentally friendly materials and refrigerants
- ▶ service-friendly construction
- ▶ optimized parameters for highest testing precision
- ▶ minimum external measurements due to compact method of construction
- ▶ minimum noise level
- ▶ extreme high temperature change rates
- ▶ simple user-friendly operation and programming
- ▶ low power-consumption data

Test space capacity in litres: 32 / 66 / 130 / 350
Temperature range: hot chamber +50° C / +200° C
 cold chamber -80° C / +100° C



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Type			TSS-70/32	TSS-70/66	TSS-70/130	TSS-70/350
Test space	litres	appr.	32	66	130	350
Test space dimensions	height	mm, appr.	300	300	410	610
	width	mm, appr.	360	420	480	850
	depth	mm, appr.	300	525	660	680
Overall dimensions	height	mm, appr.	1820 (2415*)	1820 (2415*)	1820 (2525*)	2450 (3200*)
	width	mm, appr.	820	880	940	1400 (1550**)
	depth	mm, appr.	1375	1550	2335	2200
Machine unit incl. switchboard cabinet	height	mm, appr.	----	----	----	2100
	width	mm, appr.	----	----	----	2300
	depth	mm, appr.	----	----	----	950
Temperature tests						
Temperature range	hot chamber	°C	+50/+200	+50/+200	+50/+200	+50/+200
	cold chamber	°C	-80/+100	-80/+100	-80/+100	-80/+100
Adaption time with 2,5 kg IC's	TSS-70/32	min	<15	----	----	----
Adaption time with 2,5 kg IC's	TSS-70/66	min	----	<15	----	----
Adaption time with 10 kg IC's	TSS-70/130	min	----	----	<15	----
Adaption time with 15 kg IC's	TSS-70/350	min	----	----	----	<15
Changing time		sec.	<10	<10	<10	<20
Test load, max.		kg	10	10	20	50
Temperature fluctuation		K	±1 temporally			
Nominal voltage			400 V +6% -10%, 3/N, 50 Hz			
Nominal power		kW, appr.	9,7	9,7	16,7	32,2
Refrigeration units			air cooled		water cooled	
Weight Cabinet		kg, appr.	650	700	950	1500
Mach. unit		kg, appr.	----	----	----	1000
Noise level		dB(A)	58	58	<60	<65
entry ports ø		mm	50	80	125	125

All figures are average values which have been obtained at a temperature of +25° C, without test specimens, without thermal load and without options. (* = height with spindle ** = width with spindle drive)

Design:

Control: Microprocessor control and monitoring system

Test space: Stainless steel grade 1.4301

Refrigerants: Chloride free, hermetically sealed

Options:

- ▶ add. baskets in different design
- ▶ Increased temperature range
hot chamber + 250° C (for 130 ltr.)
- ▶ add. Pt 100 for test specimen measuring
- ▶ Temperature protection for test specimen
- ▶ CID software for programming and documentation
- ▶ water cooled condenser for TSS -70/32 and TSS -70/66
- ▶ air cooled condenser for TSS -70/130 and TSS -70/350
- ▶ RS 232 interface changeable to USB
- ▶ ETHERNET- interface
- ▶ higher test load

Other chamber sizes and options on request.

We reserve the right to make alterations due to technical development.

